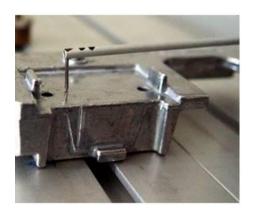
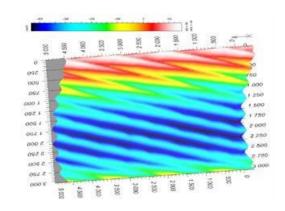




Detailed Profilometry

The Hommel somicronic surfascan is a 3D profilometer based on a stylus line scan measurement. The stylus is a rounded cone with a radius of $2\mu m$ and an opening angle of 90° . The height of the stylus pin is around 10mm. The minimal resolution in the X direction is $2\mu m$, the minimal resolution in the Y direction is $4\mu m$. The resolution of the height measurement is $0.01\mu m$, a total height difference of 6mm can be measured. The measuring speed can be varied between $0.3 \ mm/s$ up to $5 \ mm/s$. The roughness parameters are calculated according to DIN4776, the surface parameters according to DIN4762. The measurements are performed in a climate-controlled room of 20° C.





For contactless measurement of roughness, 3D measurement of wear surfaces and details, the laboratory is equipped with a Taylor-Hobson CCI HD 3D optical profiler. Further specification include: 2048×2048 pixel array for large FOV with high resolution; 0.1 Angstrom resolution over the entire measurement range; 0.3% - 100% Surface reflectivity can be accommodated; < 0.2 Angstrom RMS repeatability, < 0.1% step height repeatability. The measurements are performed in a climate-controlled climate-controlled room of 20° C.

